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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Group Art Unit: 2878

Douglas S. McGregor, et al.

Examiner: /

Serial No.: 10/695,019

Filed: October 29, 2003

For: HIGH-EFFICIENCY NEUTRON DETECTORS AND
METHODS OF MAKING SAME

Attorney Docket No.: UOM 0316 PUSP

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

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In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and § 1.97-1.98, the references listed and identified on the attached Forms PTO/SB08A and/or SB08B are being submitted herewith for consideration by the Examiner.

While this Statement is being filed in compliance with the duty of disclosure, citation of the attached references is not to be construed as an admission that any of the reference(s) are "material" as defined under 37 C.F.R. § 1.56(b).

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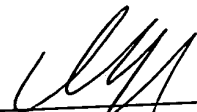
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S/N: 10/695,019

If the filing date of this application is on or before June 30, 2003, a copy of each reference listed on the attached Forms PTO/SB08A and/or SB08B is included herewith. If this application was filed after June 30, 2003, copies of any cited U.S. patent/application references have not been included. Consideration and entry into the record of these references is respectfully requested.

Respectfully submitted,

Douglas S. McGregor, et al.

By: 
David R. Syrowik
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Date: May 19, 2004

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Substitute for Form 1449B/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Complete if Known

Application Number	10/695,019
Filing Date	October 29, 2003
First Named Inventor	Douglas S. McGregor, et al.
Group Art Unit	2878
Examiner Name	
Attorney Docket Number	UOM 0316 PUSP

Sheet 1 of 1

OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		MCGREGOR, DOULGAS S., ET AL., Bulk GaAs-Based Neutron Detectors For Spent Fuel Analysis, Proceedings of ICONE 8, 8 th Int'l Conf. on Nuclear Eng., Baltimore, MD, April 2-6, 2000, pp. 1-5	
		DE LURGIO, PATRICK M., ET AL., A Neutron Detector To Monitor The Intensity of Transmitted Neutrons For Small-Angle Neutron Scattering Instruments, Elsevier Science B.V., Nuclear Instruments And Methods in Physics Research A 505, 2003, pp. 46-49	
		KLANN, RAYMOND T., ET AL., Development of Semiconductor Detectors For Fast Neutron Radiography, 15 th Int'l. conf. on Applications of Accelerators in Research and Industry, November 2000, pp. 1-4	
		GERSCH, H.K., ET AL., The Effect of Incremental Gamma-Ray Doses and Incremental Neutron Fluences Upon The Performance of Self-Biased ¹⁰ B-Coated High-Purity Epitaxial GaAs Thermal Neutron Detectors, Nuclear Instruments and Methods in Physics Research A 489, February 12, 2002, pp. 85-98	
		MCGREGOR, DOUGLAS S., ET AL., Thin-Film-Coated Detectors For Neutron Detectors, J. of Korean Asso. For Radiation Protection, Vol. 26, 2001, pp. 167-175	
		MCGREGOR, DOUGLAS, S., ET AL., Designs For Thin-Film-Coated Semiconductor Thermal Neutron Detectors, University of Michigan, Ann Arbor, Michigan, November 14, 2001, pp. 1-6	
		MCGREGOR, DOULGAS S., ET AL., Recent Results From Thin-Film-Coated Semiconductor Neutron Detectors, Proceedings of SPIE, Vol. 4784, 2002, pp. 164-182	

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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